Se	arcn Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/618,637	MOK, JIN-YOUNG	
Examiner	Art Unit	
Tu X Nauven	2618	

	SEARCHED			
Class	Subclass	Date	Examiner	
455	575.3	9/20/2006	TN	
	550.1			
	557			
	556			
	575.1			
379	58			
	433.13			
	433.11			
	433.12			
	433.09			
	,			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
455	575.3	9/20/2006		
379	433.13			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Search East	9/20/2006	TN
Jack Chiang	4/18/2006	